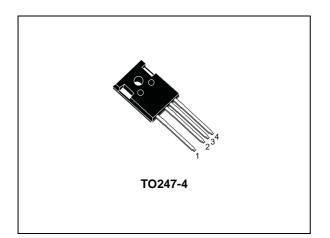


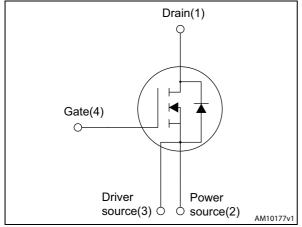
# STW69N65M5-4

Datasheet - production data

### N-channel 650 V, 0.037 Ω typ., 58 A, MDmesh<sup>™</sup> V Power MOSFET in a TO247-4 package



#### Figure 1. Internal schematic diagram



#### Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STW69N65M5-4	710 V	0.045 Ω	58 A

- Higher V<sub>DS</sub> rating
- Higher dv/dt capability
- Excellent switching performance thanks to the extra driving source pin
- Easy to drive
- 100% avalanche tested

### **Applications**

- High efficiency switching applications:
  - Servers
  - PV inverters
  - Telecom infrastructure
  - Multi kW battery chargers

### Description

This device is an N-channel MDmesh<sup>™</sup> V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH<sup>™</sup> horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

#### Table 1. Device summary

Order code Marking		Package	Packaging
STW69N65M5-4 69N65M5		TO247-4	Tube

DocID024925 Rev 2

This is information on a product in full production.

## Contents

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	2.1 Electrical characteristics (curves)
3	Test circuits
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## 1 Electrical ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate- source voltage	±25	V
۱ <sub>D</sub>	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	58	Α
۱ <sub>D</sub>	Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	36.5	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	232	А
P <sub>TOT</sub>	Total dissipation at $T_C = 25 \ ^{\circ}C$	330	W
I <sub>AR</sub>	Max current during repetitive or single pulse avalanche (pulse width limited by ${\rm T}_{\rm JMAX}$ )	12	A
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	1410	mJ
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	15	V/ns
dv/dt <sup>(3)</sup>	MOSFET dv/dt ruggedness	50	V/ns
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C
Тj	Max. operating junction temperature	150	°C

#### Table 2. Absolute maximum ratings

1. Pulse width limited by safe operating area

2. I\_{SD}  $\,\leq$  58 A, di/dt = 400 A/ $\mu$ s, peak V\_{DS} < V\_{(BR)DSS}, V\_{DD} = 400 V

3.  $V_{DS} \leq 520 V$ 

#### Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.38	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max	50	°C/W



### 2 Electrical characteristics

(T<sub>C</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	650			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 650 V V <sub>DS</sub> = 650 V, T <sub>C</sub> =125 °C			1 100	μΑ μΑ
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 25 V			± 100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 29 A		0.037	0.045	Ω

Table	4.	On	/off	states
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Tabl	е 5.	Dyna	amic
IUNI	<b>U</b> U.	Dyne	

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
C <sub>iss</sub>	Input capacitance		-	6420	-	pF	
C <sub>oss</sub>	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz,	-	170	-	pF	
C <sub>rss</sub>	Reverse transfer capacitance	V <sub>GS</sub> = 0	-	11	-	pF	
C <sub>o(tr)</sub> <sup>(1)</sup>	Equivalent capacitance time related	$V_{GS} = 0, V_{DS} = 0$ to 520 V	-	536	-	pF	
C <sub>o(er)</sub> <sup>(2)</sup>	Equivalent capacitance energy related	$V_{GS} = 0, V_{DS} = 0$ to 520 V	-	146	-	pF	
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz open drain	-	1.3	-	Ω	
Qg	Total gate charge	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 29 A,	-	143	-	nC	
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V	-	38	-	nC	
Q <sub>gd</sub>	Gate-drain charge	(see Figure 16)	-	64	-	nC	

1.  $C_{o(tr)}$  is a constant capacitance value that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

2.  $C_{o(er)}$  is a constant capacitance value that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit		
t <sub>d(V)</sub>	Voltage delay time	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 38 A,	-	102	-	ns		
t <sub>r(V)</sub>	Voltage rise time	$R_{G} = 4.7 \Omega, V_{GS} = 10 V$	-	10	-	ns		
t <sub>f(i)</sub>	Current fall time	(see Figure 17)	-	11.5	-	ns		
t <sub>c(off)</sub>	Crossing time	(see <i>Figure 20</i> )	-	14.5	-	ns		

Table 6. Switching times

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		58	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		232	А
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 58 A, V <sub>GS</sub> = 0	-		1.5	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 58 A,	-	480		ns
Q <sub>rr</sub>	Reverse recovery charge	di/dt = 100 A/µs	-	11		μC
I <sub>RRM</sub>	Reverse recovery current	$v_{DD} = 100 V (see Figure 17)$		46		А
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 58 A,	-	592		ns
Q <sub>rr</sub>	Reverse recovery charge	erse recovery charge di/dt = 100 A/μs V <sub>DD</sub> = 100 V, T <sub>i</sub> = 150 °C		16		μC
I <sub>RRM</sub>	Reverse recovery current	(see <i>Figure 17</i> )	-	53		А

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration =  $300 \,\mu$ s, duty cycle 1.5%



### 2.1 Electrical characteristics (curves)

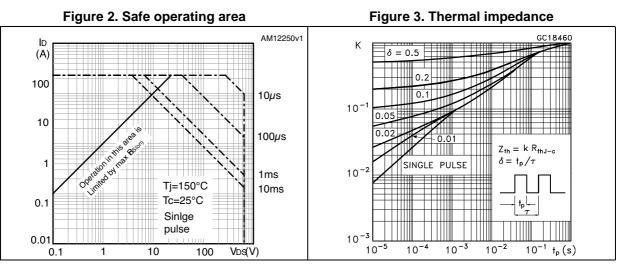
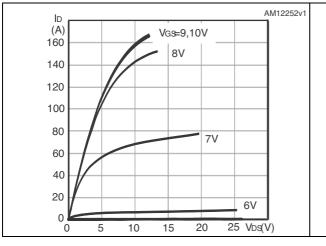


Figure 4. Output characteristics





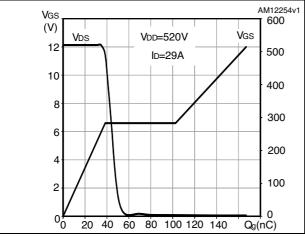


Figure 5. Transfer characteristics

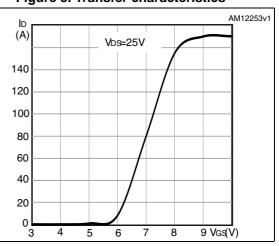
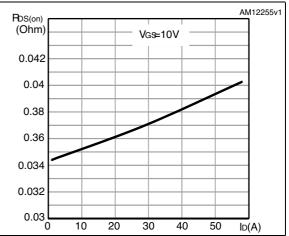


Figure 7. Static drain-source on-resistance





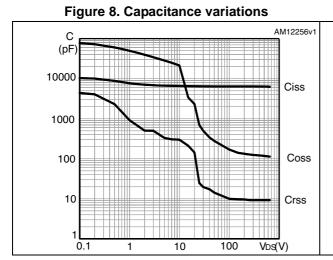


Figure 10. Normalized gate threshold voltage vs temperature

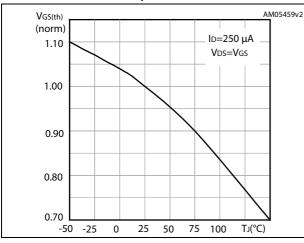
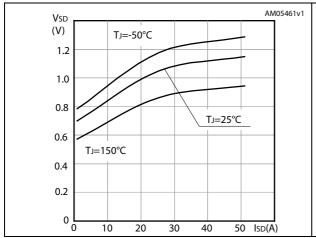
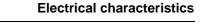


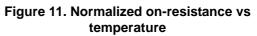
Figure 12. Source-drain diode forward characteristics





AM12257v1 Eoss (µJ) 30 25 20 15 10 5 0 100 200 300 400 500 600 VDs(V) 0

Figure 9. Output capacitance stored energy



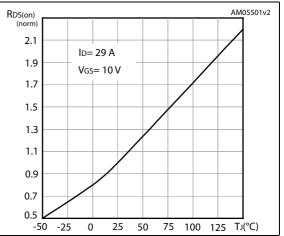
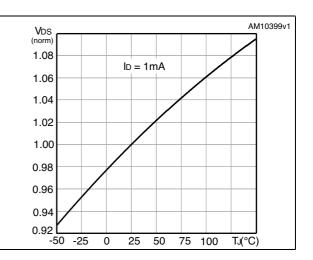


Figure 13. Normalized  $V_{DS}$  vs temperature





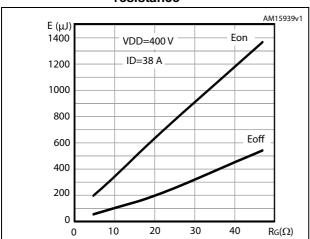


Figure 14. Switching losses vs gate resistance <sup>(1)</sup>

1. Eon including reverse recovery of a SiC diode.

#### **Test circuits** 3

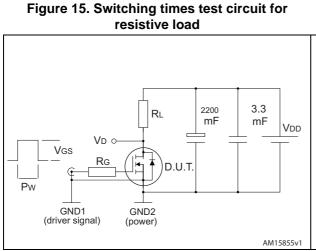


Figure 17. Test circuit for inductive load switching and diode recovery times

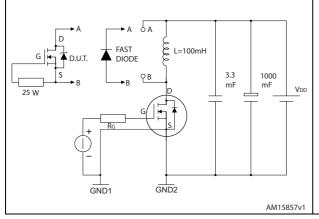
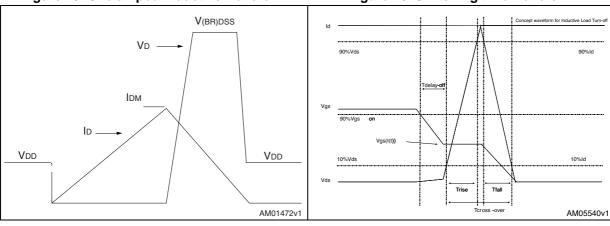


Figure 19. Unclamped inductive waveform



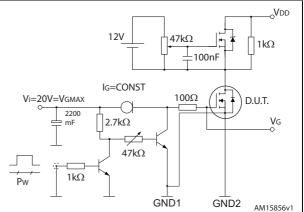
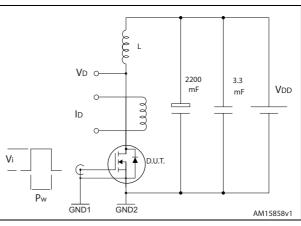
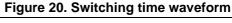


Figure 16. Gate charge test circuit









e Load Turn-o

90%ld

#### Package mechanical data 4

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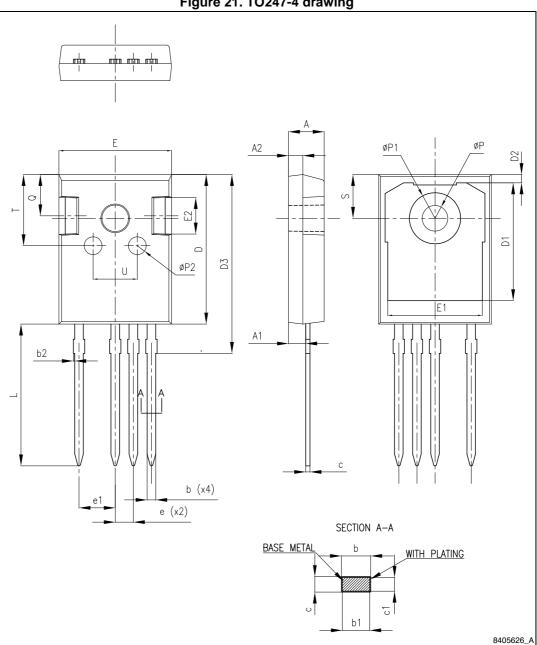


Figure 21. TO247-4 drawing



Table 8. TO247-4 mechanical data						
Dim.		mm.				
Dim.	Min.	Тур.	Max.			
А	4.90	5.00	5.10			
A1	2.31	2.41	2.51			
A2	1.90	2.00	2.10			
b	1.16		1.29			
b1	1.15	1.20	1.25			
b2	0		0.20			
с	0.59		0.66			
c1	0.58	0.60	0.62			
D	20.90	21.00	21.10			
D1	16.25	16.55	16.85			
D2	1.05	1.20	1.35			
D3	24.97	25.12	25.27			
E	15.70	15.80	15.90			
E1	13.10	13.30	13.50			
E2	4.90	5.00	5.10			
E3	2.40	2.50	2.60			
е	2.44	2.54	2.64			
e1	4.98	5.08	5.18			
L	19.80	19.92	20.10			
Р	3.50	3.60	3.70			
P1			7.40			
P2	2.40	2.50	2.60			
Q	5.60		6.00			
S		6.15				
Т	9.80		10.20			
U	6.00		6.40			

Table 8. TO247-4 mechanical data



## 5 Revision history

Date	Revision	Changes
28-Jun-2013	1	Initial release.
17-Jan-2014	2	Document status promoted from preliminary to production data.

#### Table 9. Document revision history



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